



STRUCTURAL
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Supporting information for article:

Crystal structure of the thortveitite-related *M* phase, $(\text{Mn}_x\text{Zn}_{1-x})_2\text{V}_2\text{O}_7$ ($0.75 < x < 0.913$): a combined synchrotron powder and single-crystal X-ray study

Kevin M. Knowles, Anjan Sil, Berthold Stöger and Matthias Weil

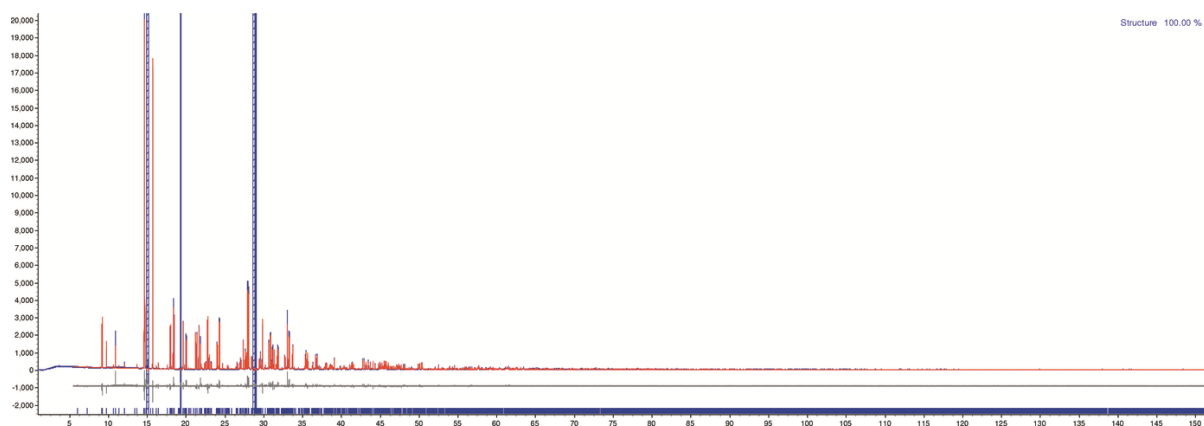


Figure 1: Synchrotron X-ray diffraction pattern obtained from the *M* phase covering the entire range from which reflections were recorded together with the difference plot in grey between the experimental data in blue and the fitted X-ray diffraction pattern obtained by Rietveld refinement in red. Reflections identifiable at low angles as not being from *M* phase were excluded from the Rietveld analysis and are shown as blue shaded regions.

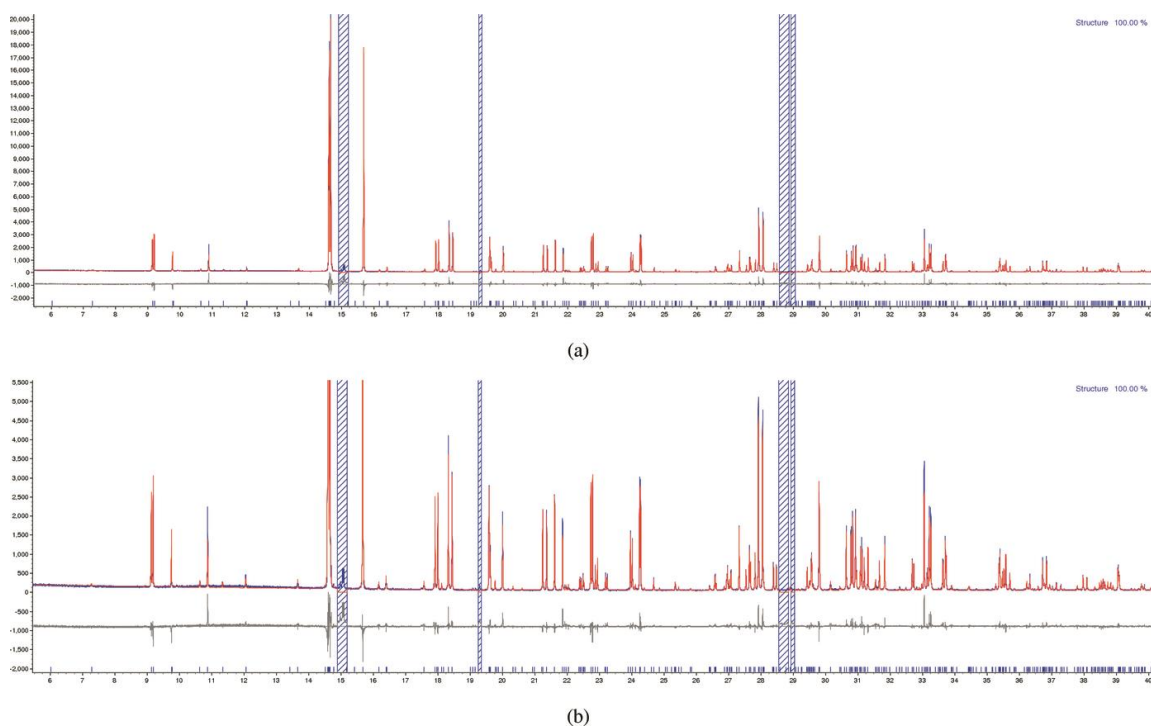
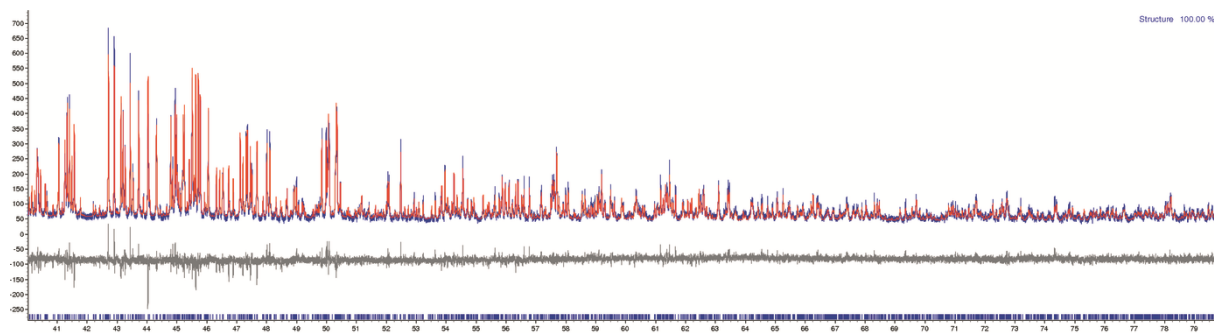
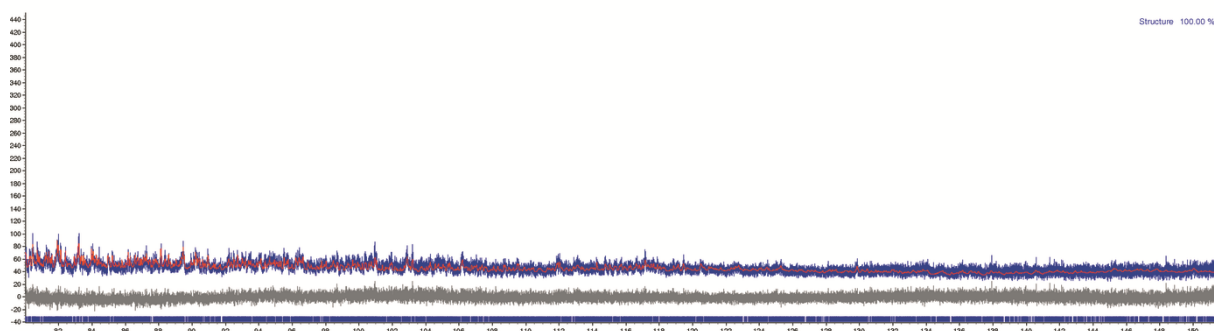


Figure 2: Enlargement of the synchrotron X-ray diffraction pattern for the region 5.5–40°. (a) is the whole pattern of counts within this angular range and (b) is an enlargement of (a) with an upper count limit of 5,500.



(a)



(b)

Figure 3: Enlargement of the synchrotron X-ray diffraction pattern for the regions (a) 40–80° and (b) 80–152°.